



IEEE Instrumentation and Measurement Technology Conference

A view on the new technologies for instrumentation and measurements

Hilton Sorrento Palace, Sorrento, ITALY
 24-27 April 2006 (Monday - Thursday)

Call for Papers

The conference focuses on all aspects of instrumentation, measurement and control technologies - theory, research and development and applications. Program topics include but are not limited to:

MEASUREMENT SCIENCE

Metrology & standards
 Measurement principles education

DATA ACQUISITION

Sensors & transducers, smart sensors
 Calibration & self-calibration
 A/D, D/A & data acquisition
 Remote measurements & telemetry
 Waveform measurement, analysis & generation
 Sensitivity & noise

INSTRUMENTATION TECHNOLOGIES

Automated test & measurement systems
 Instrumentation & prototype development
 Frequency, microwave and laser I&M systems
 Integrated & visual measurement systems
 Human-computer interface
 Networked & distributed measurements
 Autonomous sensing & measurement systems
 Non-invasive instrumentation & measurement
 Measurement microsystems
 Testing & diagnosis of I&M systems
 Fault-tolerant & resilient I&M systems

DATA PROCESSING TECHNOLOGIES

Analog, digital & mixed-signal processing
 Image processing & imaging systems
 Identification, control & distributed monitoring
 System prediction & sensor fusion
 Soft computing for intelligent I&M systems

PHYSICAL QUANTITIES MEASUREMENTS

Electrical & power measurements
 Dielectric, magnetic and EMC measurements
 Temperature, moisture & humidity measurements
 Mechanical quantities & material analysis
 Optical & nuclear measurements
 Chemical & biological measurements

MEASUREMENT APPLICATIONS

Robotics, industrial automation & manufacturing
 Automotive & transportation
 Avionics & aerospace
 Environmental monitoring
 Medicine & science
 Security & biometrics
 Telecommunications
 Virtual environments

IMTC/06 will offer a day of tutorials on Monday, 24 April. Proposals for tutorial presentations can be submitted before 1 January 2006 to lee.myers@ieee.org.

Authors will submit electronically 1 copy of an extended abstract (3 or 4 pages) *in English*, reflecting new or advanced study, theory or application and including the significance of the contribution, a list of references and figures or tables. Abstracts must be prepared according to the Abstract Preparation Guide and must be accompanied by an Abstract Submission Form. Both documents may be downloaded from the IMTC website – <http://www.ieee-imtc.org>. Check the website for all instructions and details. Important dates:

- **3 October 2005** – Abstract submission deadline – submit to lee.myers@ieee.org
- **19 December 2005** – Author notification of acceptance or rejection
- **4 March 2006** – Deadline for receipt of final manuscript

Papers will be reviewed by the IMTC International Program Committee. Authors of accepted abstracts *must guarantee they will register for the conference, pay registration fees, attend and present their papers*. An accepted paper will be published in the proceedings only if the final manuscript is accompanied by registration form(s) and fee(s) for at least one of the authors (*only full member/non-member registration fees will be allowed – no Student or Life Member fees!*). One author registration covers publication of up to 2 accepted papers; each additional paper under the same registration requires a publication fee of US\$50. Authors of accepted and presented papers may submit extended manuscripts to the special issue of *IEEE Transactions on Instrumentation & Measurement* on IMTC/2006, to be published in 2007.

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